## Applicant(s)/Patent Under Application/Control No. Reexamination 10/830,049 OHNISHI ET AL. Notice of References Cited Art Unit Examiner Page 1 of 1 Linh V. Nguyen 2819 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY \* US-2005/0134389 A1 06-2005 Scherrer et al. 330/310 Α В US-6,456,125 B1 09-2002 Miyazawa, Shigemi 327/113 С US-5,973,567 A 10-1999 Heal et al. 330/286 US-D US-Ε US-F US-G US-Н USı US-J Κ US-US-L US-М **FOREIGN PATENT DOCUMENTS Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν O Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U

W

Х

<sup>\*</sup>A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.